



Final Product Change Notification

201907008F01

Issue Date: 04-Aug-2019
Effective Date: 01-Nov-2019

Here's your personalized quality information concerning products Digi-Key purchased from NXP. For detailed information we invite you to view this notification online



QUALITY

This notice is NXP Company Proprietary.

Change Category

- | | | | | |
|--|--|--|---|---|
| <input type="checkbox"/> Wafer Fab Process | <input type="checkbox"/> Assembly Process | <input type="checkbox"/> Product Marking | <input type="checkbox"/> Test Location | <input type="checkbox"/> Design |
| <input type="checkbox"/> Wafer Fab Materials | <input type="checkbox"/> Assembly Materials | <input type="checkbox"/> Mechanical Specification | <input type="checkbox"/> Test Process | <input type="checkbox"/> Errata |
| <input type="checkbox"/> Wafer Fab Location | <input checked="" type="checkbox"/> Assembly Location | <input type="checkbox"/> Packing/Shipping/Labeling | <input type="checkbox"/> Test Equipment | <input type="checkbox"/> Electrical spec./Test coverage |
| <input type="checkbox"/> Firmware | <input checked="" type="checkbox"/> Other - Die thickness and package substrate trace spacing modification | | | |

SPC5777C/B/E Die Thickness Increase to 280um, Substrate Trace Spacing Modification and NXP-ATKL Assembly Site Expansion

Description of Change

NXP Semiconductors announces the following changes for the SPC5777C/ B/ E, Mask Set N45H products associated with this notification:

1. Die thickness increase from the current 179um to 280um.
2. Package substrate trace spacing modification between EXTAL and ETPUB31 will be increased.
3. Assembly site expansion from the current NXP-ATTJ, Tianjin, China assembly facility to the NXP-ATKL, Kuala Lumpur, Malaysia assembly facility.

For more information about the substrate trace spacing modification, please refer to the "Communication Package" file attached.

For the assembly site expansion, there is no change to the package bill of material (BOM) between the two assembly sites.

The above changes coincides with DeQuMa ID: SEM-PW-03, SEM-PA-09 and SEM-PA-18.

Reason for Change

Die thickness increase is to improve product quality, reliability and C55 product family standardization.

Substrate trace spacing modification is to improve device oscillator clock stability.

Site expansion qualification is required for manufacturing flexibility and customer supply assurance.

Identification of Affected Products

There is no change to the product part number marking.

The assembly site, among other information, is reflected in the package trace code.

Please refer to the marking explanation in the "Communication Package" file attached.

Product Availability

Sample Information

Samples are available upon request

Sample part numbers information is available in the "Communication Package" file attached.

Production

Planned first shipment 20-Dec-2019

Anticipated Impact on Form, Fit, Function, Reliability or Quality

No impact on form, fit, function, reliability or quality.

Disposition of Old Products

Existing inventory for substrate will be shipped until depleted.

For Assembly site expansion, no depletion of inventory required.

Timing and Logistics

In compliance with JEDEC J-STD-046, your acknowledgement of this change is expected by 03-Sep-2019.

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

At NXP Semiconductors we are constantly striving to improve our product and processes to ensure they reach the highest possible Quality Standards.

Customer Focus, Passion to Win.

NXP Quality Management Team.

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NXP Semiconductors

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Affected Part Numbers

SPC5777CCK3MME3

SPC5777CK3MMO3

SPC5777CK3MME3

SPC5775BDK3MME2

SPC5777CDK3MMO3

SPC5777CDK3MME4

SPC5777CDK3MMO4

SPC5775EDK3MME3

SPC5777CDK3MME3

Affected 12NC

935315842557

935318909557

935320923557

935371593557

935350951557

935368231557

935368233557

935370091557

935350948557